

TENTATIVE TOSHIBA CCD LINEAR IMAGE SENSOR CCD(Charge Coupled Device)

TCD1501C

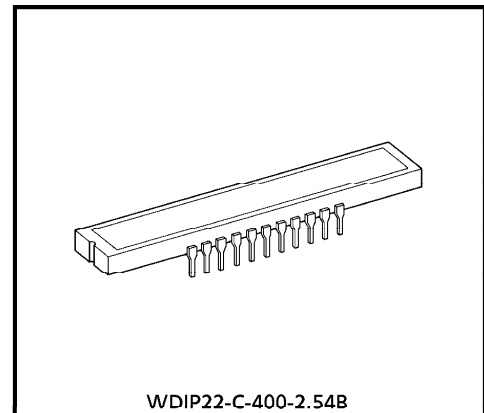
The TCD1501C which includes sample-and-hold circuit is a high sensitive and low dark current 5000 elements CCD image sensor.

The sensor is designed for facsimile, imagescanner and OCR.

The device contains a row of 5000 elements photodiodes which provide a 16 lines / mm (400DPI) across a A3 size paper. The device is operated by 5V (pulse), and 12V power supply.

FEATURES

- Number of Image Sensing Elements : 5000 elements
- Image Sensing Element Size : 7 μ m by 7 μ m on 7 μ m centers
- Photo Sensing Region : High sensitive and low voltage dark signal pn photodiode
- Clock : 2 Phase (5V)
- Internal Circuit : S / H circuit
- Package : 22pin DIP



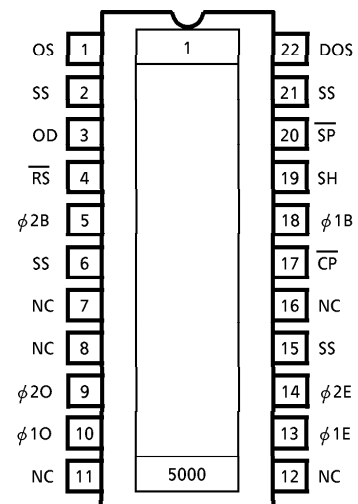
Weight : 5.4g (Typ.)

MAXIMUM RATINGS (Note 1)

| CHARACTERISTIC | SYMBOL | RATING | UNIT |
|-------------------------------|------------|----------|------|
| Clock Pulse Voltage | V_{ϕ} | - 0.3~8 | V |
| Shift Pulse Voltage | V_{SH} | | |
| Reset Pulse Voltage | V_{RS} | | |
| Clamp Pulse Voltage | V_{CP} | | |
| Sample and Hold Pulse Voltage | V_{SP} | | |
| Power Supply Voltage | V_{OD} | - 0.3~15 | |
| Operating Temperature | T_{opr} | - 25~60 | °C |
| Storage Temperature | T_{stg} | - 40~100 | °C |

(Note 1) All voltage are with respect to SS terminals (Ground).

PIN CONNECTIONS

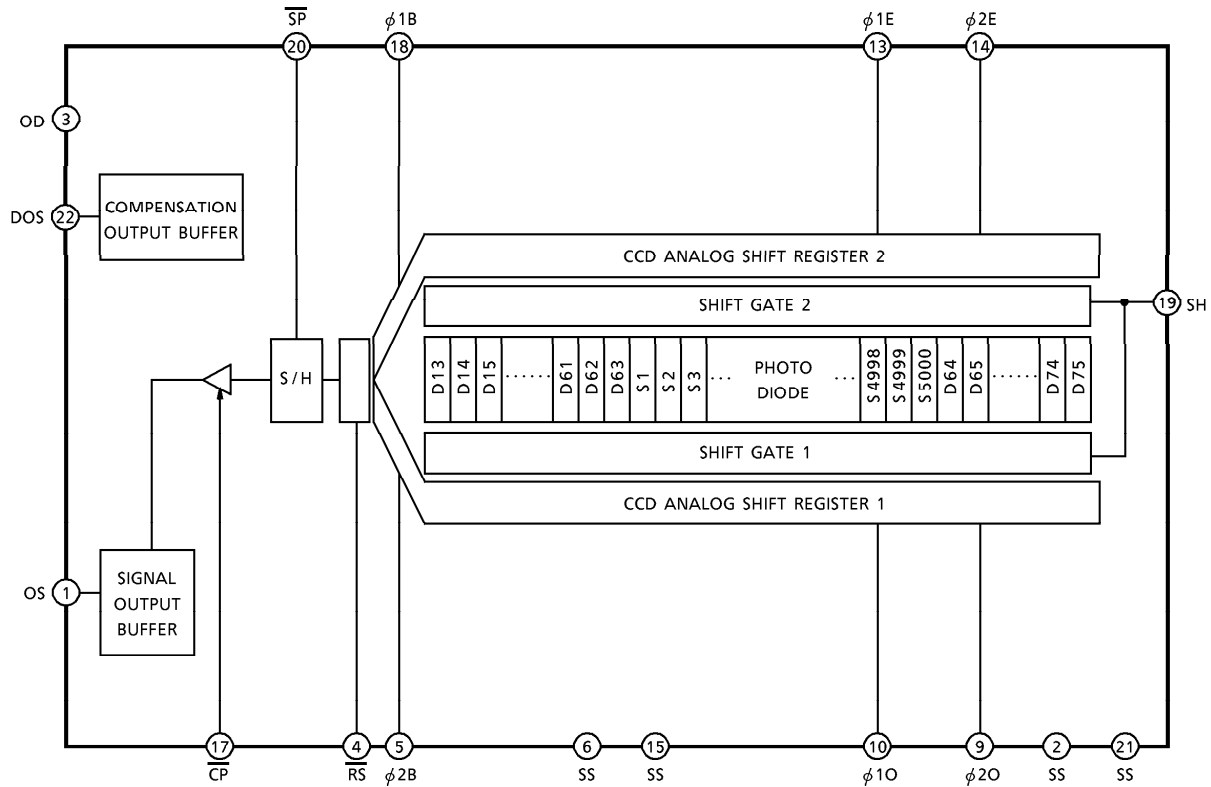


(TOP VIEW)

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CIRCUIT DIAGRAM



PIN NAME

| | |
|-----------------|-----------------------------|
| $\phi 1E, O$ | Clock (Phase 1) |
| $\phi 2E, O$ | Clock (Phase 2) |
| $\phi 1B$ | Final Stage Clock (Phase 1) |
| $\phi 2B$ | Final Stage Clock (Phase 2) |
| SH | Shift Gate |
| \overline{RS} | Reset Gate |
| \overline{SP} | Sample and Hold Gate |
| \overline{CP} | Clamp Gate |
| OS | Signal Output |
| DOS | Compensation Output |
| OD | Power |
| SS | Ground |
| NC | Non Connection |

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OPTICAL / ELECTRICAL CHARACTERISTICS

(Ta = 25°C, V_{OD} = 12V, V_φ = V_{RS} = V_{SH} = V_{SP} = V_{CP} = 5V, f_φ = 0.5MHz, f_{RS} = 1MHz, t_{INT} (INTEGRATION TIME) = 10ms, LIGHT SOURCE = DAYLIGHT FLUORESCENT LAMP, LOAD RESISTANCE = 100kΩ)

| CHARACTERISTIC | SYMBOL | MIN. | TYP. | MAX. | UNIT | NOTE |
|--------------------------------|-----------------------------------|------|------|------|----------|----------|
| Sensitivity | R | 10.4 | 13 | 15.6 | V / lx·s | |
| Photo Response Non Uniformity | PRNU | — | — | 10 | % | (Note 2) |
| | PRNU (3) | — | 6 | 10 | mV | (Note 9) |
| Register Imbalance | RI | — | — | 3 | % | (Note 3) |
| Saturation Output Voltage | V _{SAT} | 2 | 3 | — | V | (Note 4) |
| Saturation Exposure | SE | 0.13 | 0.23 | — | lx·s | (Note 5) |
| Dark Signal Voltage | V _{DRK} | — | 1 | 2 | mV | (Note 6) |
| Dark Signal Non Uniformity | DSNU | — | 2 | 3 | mV | (Note 6) |
| DC Power Dissipation | P _D | — | 240 | 325 | mW | |
| Total Transfer Efficiency | TTE | 92 | — | — | % | |
| Output Impedance | Z _O | — | 0.5 | 1 | kΩ | |
| Dynamic Range | DR | — | 3000 | — | — | (Note 7) |
| DC Signal Output Voltage | V _{OS} | 4 | 5 | 6.5 | V | (Note 8) |
| DC Compensation Output Voltage | V _{DOS} | 4 | 5 | 6.5 | V | (Note 8) |
| DC Differential Error Voltage | V _{OS} -V _{DOS} | — | — | 400 | mV | |

(Note 2) Measured at 50% of SE (Typ.)

$$\text{Definition of PRNU : PRNU} = \frac{\Delta x}{\bar{x}} \times 100 (\%)$$

Where \bar{x} is average of total signal output and Δx is the maximum deviation from \bar{x} under uniform illumination.

(Note 3) Measured at 50% of SE (Typ.)

RI is defined as follows:

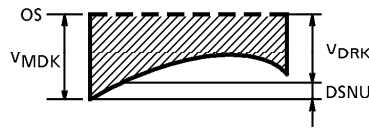
$$RI = \frac{\sum_{n=1}^{4999} |x_n - x_{n+1}|}{4999 \times \bar{x}} \times 100 (\%)$$

Where x_n and x_{n+1} are signal output of each pixel. \bar{x} is average of total signal output.

(Note 4) V_{SAT} is defined as minimum saturation output voltage of all effective pixels.

(Note 5) Definition of SE : $SE = \frac{V_{SAT}}{R} (I \times s)$

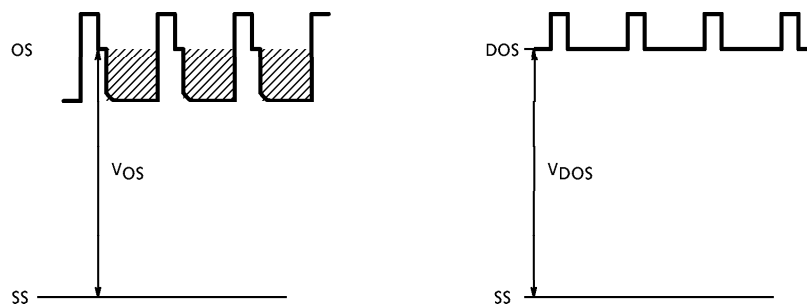
(Note 6) V_{DRK} is defined as average dark signal voltage of all effective pixels.
 $DSNU$ is defined as different voltage between V_{DRK} and V_{MDK} when V_{MDK} is maximum dark signal voltage.



(Note 7) Definition of DR : $DR = \frac{V_{SAT}}{V_{DRK}}$

V_{DRK} is proportional to t_{INT} (Integration Time).
 So the shorter t_{INT} condition makes wider DR values.

(Note 8) DC signal output voltage and DC compensation output voltage are defined as follows:



(Note 9) PRUN(3) is defined as maximum voltage with next pixel, where measured 5% of SE (Typ.).

OPERATING CONDITION

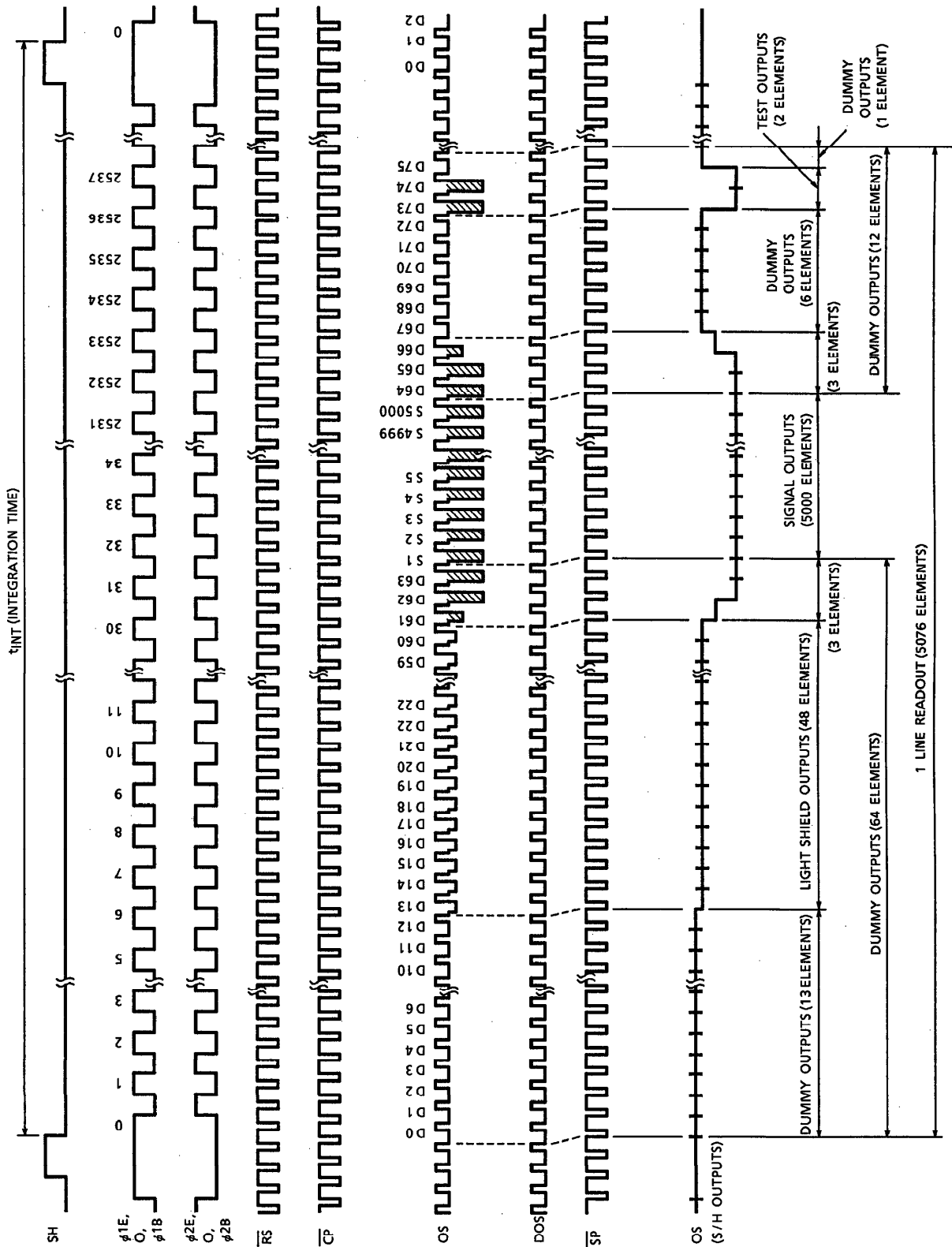
| CHARACTERISTIC | | SYMBOL | MIN. | TYP. | MAX. | UNIT |
|---------------------------------|-----------|------------------|------|------|------|------|
| Clock Pulse Voltage | "H" Level | $V_{\phi 1E, O}$ | 4.5 | 5 | 5.5 | V |
| | "L" Level | $V_{\phi 2E, O}$ | 0 | — | 0.5 | |
| Final Stage Clock Voltage | "H" Level | $V_{\phi 1B}$ | 4.5 | 5 | 5.5 | V |
| | "L" Level | $V_{\phi 2B}$ | 0 | — | 0.5 | |
| Shift Pulse Voltage | "H" Level | V_{SH} | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Reset Pulse Voltage | "H" Level | V_{RS} | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Clamp Pulse Voltage | "H" Level | V_{CP} | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Sample and Hold Pulse Voltage * | "H" Level | V_{SP} | 4.5 | 5 | 5.5 | V |
| | "L" Level | | 0 | — | 0.5 | |
| Power Supply Voltage | | V_{OD} | 11.4 | 12.0 | 13.0 | V |

* Supply "L" level to \overline{SP} terminal when sample-and-hold circuitry is not used.

CLOCK CHARACTERISTICS (Ta = 25°C)

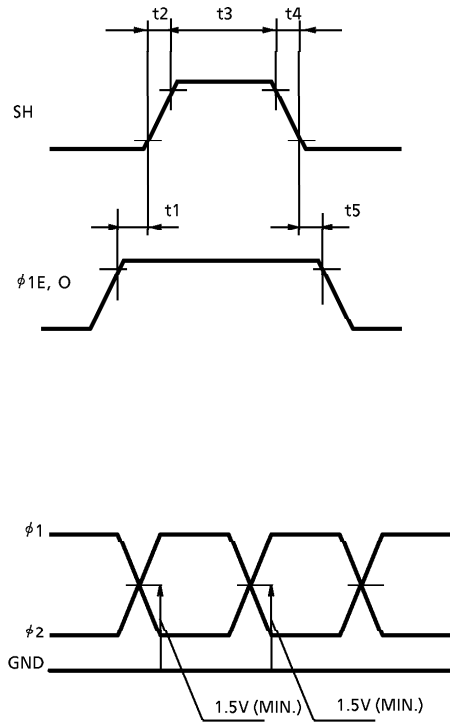
| CHARACTERISTIC | SYMBOL | MIN. | TYP. | MAX. | UNIT |
|----------------------------------|---------------------|------|------|------|------|
| Clock Pulse Frequency | f_{ϕ} | — | 0.5 | 6.0 | MHz |
| Reset Pulse Frequency | $f_{\overline{RS}}$ | — | 1.0 | 12.0 | MHz |
| Sample and Hold Pulse Frequency | $f_{\overline{SP}}$ | — | 1.0 | 2.0 | MHz |
| Clock Capacitance | $C_{\phi E}$ | — | 350 | 450 | pF |
| | $C_{\phi O}$ | — | 350 | 450 | |
| Final Stage Clock Capacitance | $C_{\phi B}$ | — | 10 | 20 | pF |
| Shift Gate Capacitance | C_{SH} | — | 10 | 20 | pF |
| Reset Gate Capacitance | $C_{\overline{RS}}$ | — | 10 | 20 | pF |
| Clamp Gate Capacitance | $C_{\overline{CP}}$ | — | 10 | 20 | pF |
| Sample and Hold Gate Capacitance | $C_{\overline{SP}}$ | — | 10 | 20 | pF |

TIMING CHART

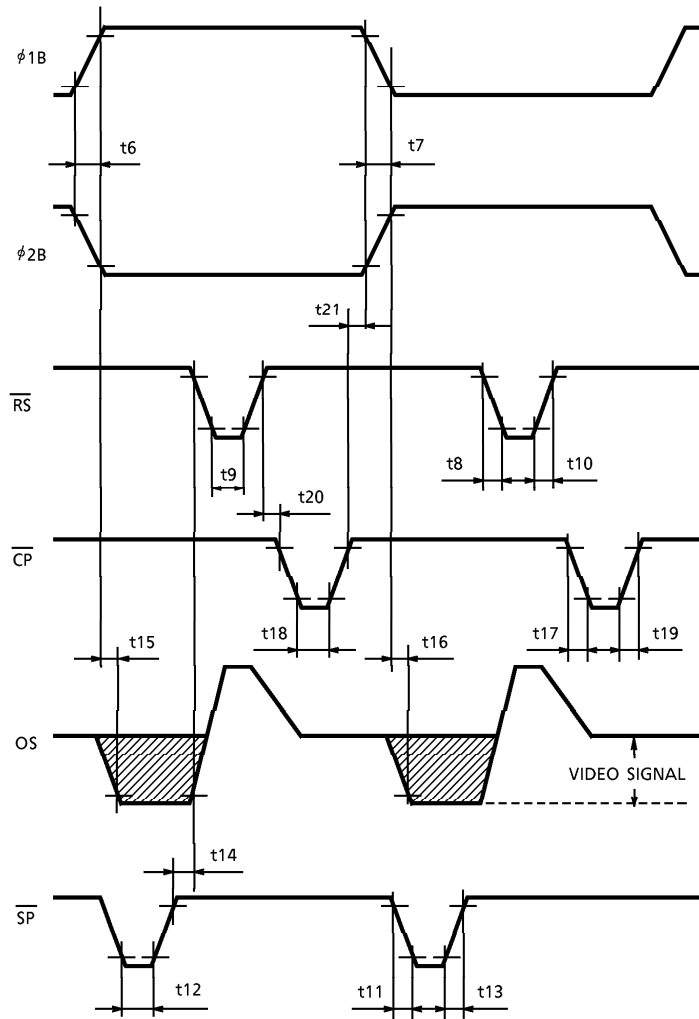


TIMING REQUIREMENTS

SH, $\phi 1$ TIMING



$\phi 1$, $\phi 2$, \overline{RS} , \overline{CP} , OS, \overline{SP} TIMING

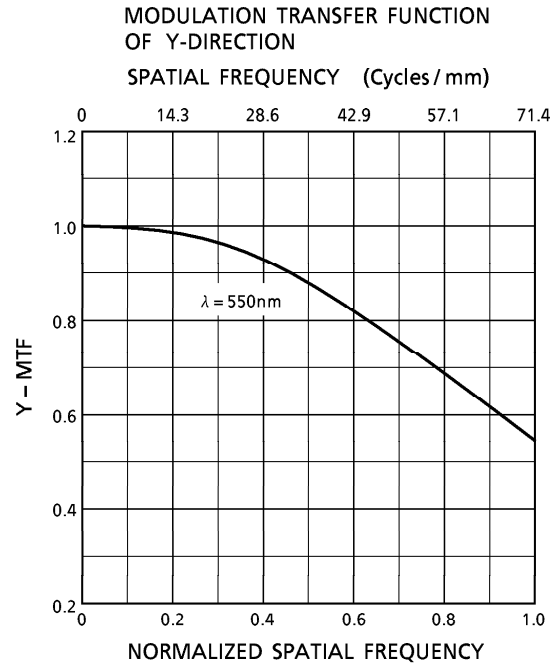
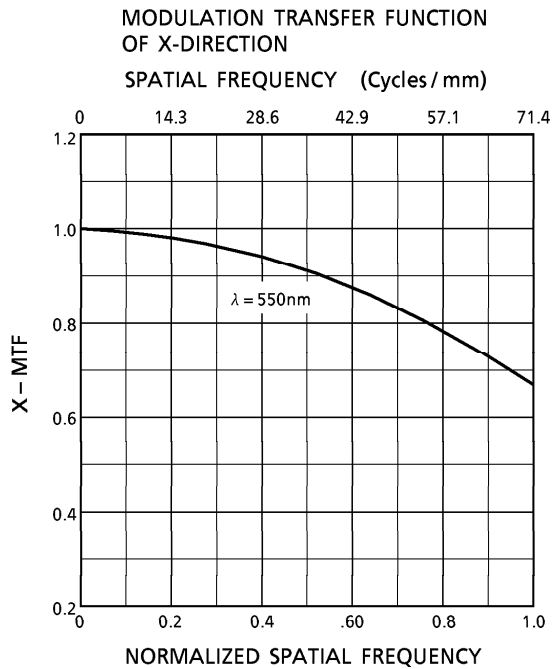
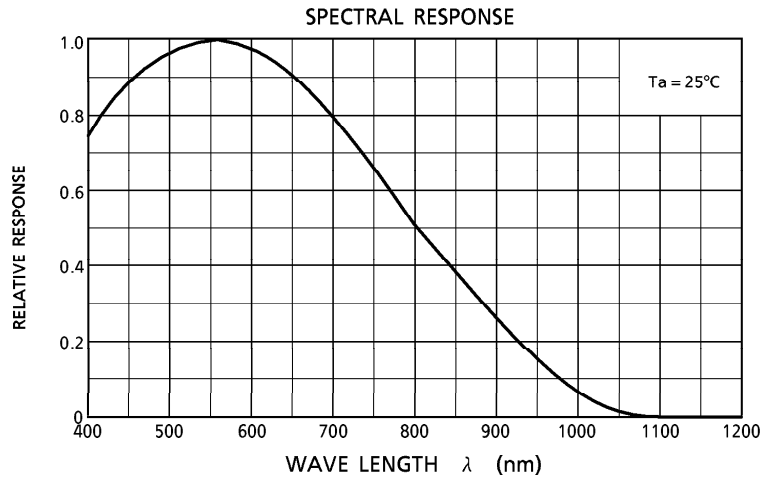


| CHARACTERISTIC | SYMBOL | MIN. | TYP. (Note 10) | MAX. | UNIT |
|---|----------|------|-------------------|------|------|
| Pulse Timing of SH and ϕ 10, E | t1, t5 | 100 | 300 | — | ns |
| SH Pulse Rise Time, Fall Time | t2, t4 | 0 | 50 | — | ns |
| SH Pulse Width | t3 | 500 | 1000 | — | ns |
| ϕ 1, ϕ 2 Pulse Rise Time, Fall Time | t6, t7 | 0 | 100 | — | ns |
| RS Pulse Rise Time, Fall Time | t8, t10 | 0 | 20 | — | ns |
| RS Pulse Width | t9 | 20 | 250 | — | ns |
| SP Pulse Rise Time, Fall Time | t11, t13 | 0 | 20 | — | ns |
| SP Pulse Width | t12 | 20 | — | — | ns |
| Pulse Timing of SP and RS | t14 | 0 | 50 | — | ns |
| Video Data Delay Time (Note 11) | t15, t16 | — | 30 | — | ns |
| CP Pulse Rise Time, Fall Time | t17, t19 | 0 | 20 | — | ns |
| CP Pulse Width | t18 | 20 | — | — | ns |
| Pulse Timing of RS and CP | t20 | 0 | — | — | ns |
| Pulse Timing of ϕ 1B, ϕ 2B and CP | t21 | 0 | — | — | ns |

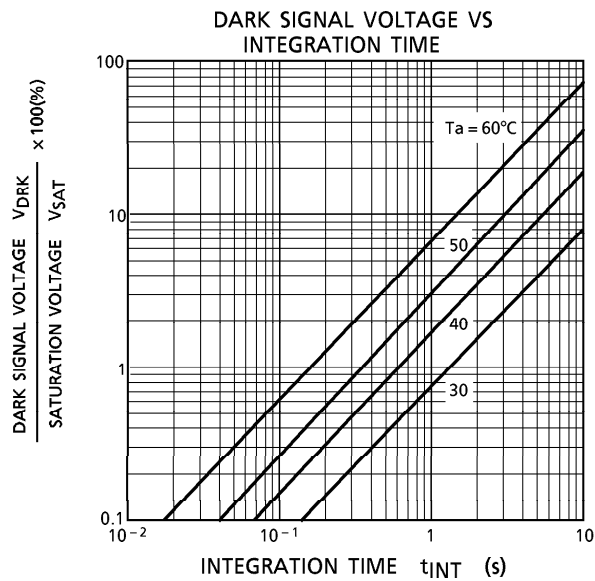
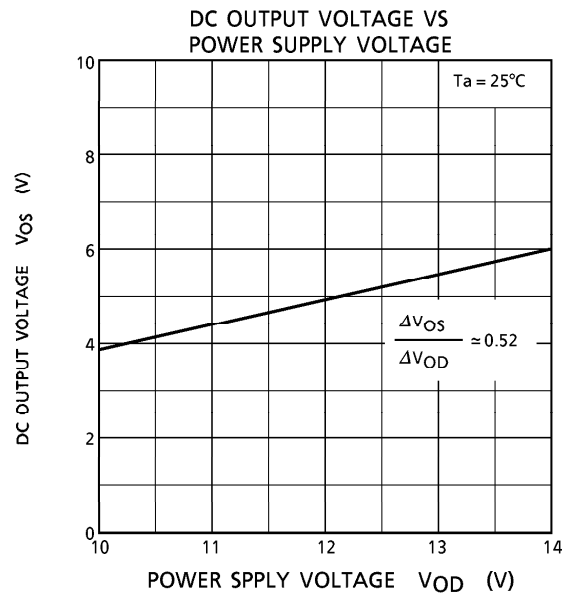
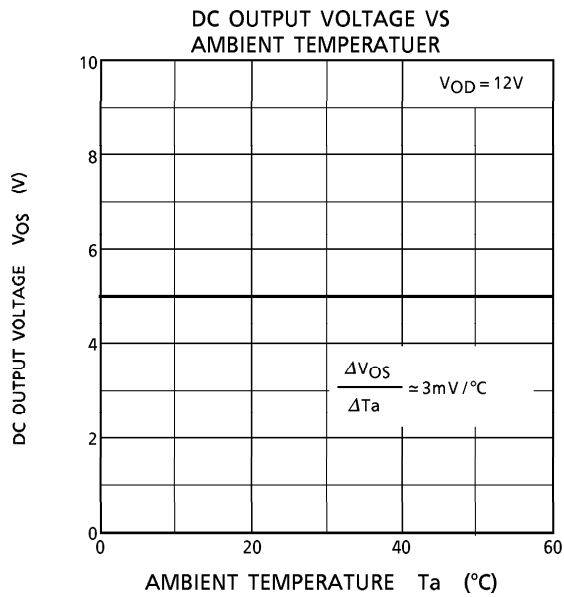
(Note 10) TYP. is the case of $f_{RS} = 1.0\text{MHz}$

(Note 11) Load Resistance is $100\text{k}\Omega$

TYPICAL PERFORMANCE CURVES



TYPICAL PERFORMANCE CURVES (Cont'd)



CAUTION**1. Window Glass**

The dust and stain on the glass window of the package degrade optical performance of CCD sensor.

Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N₂.

Care should be taken to avoid mechanical or thermal shock because the glass window is easily damaged.

2. Electrostatic Breakdown

Store in shorting clip or in conductive foam to avoid electrostatic breakdown.

3. Incident Light

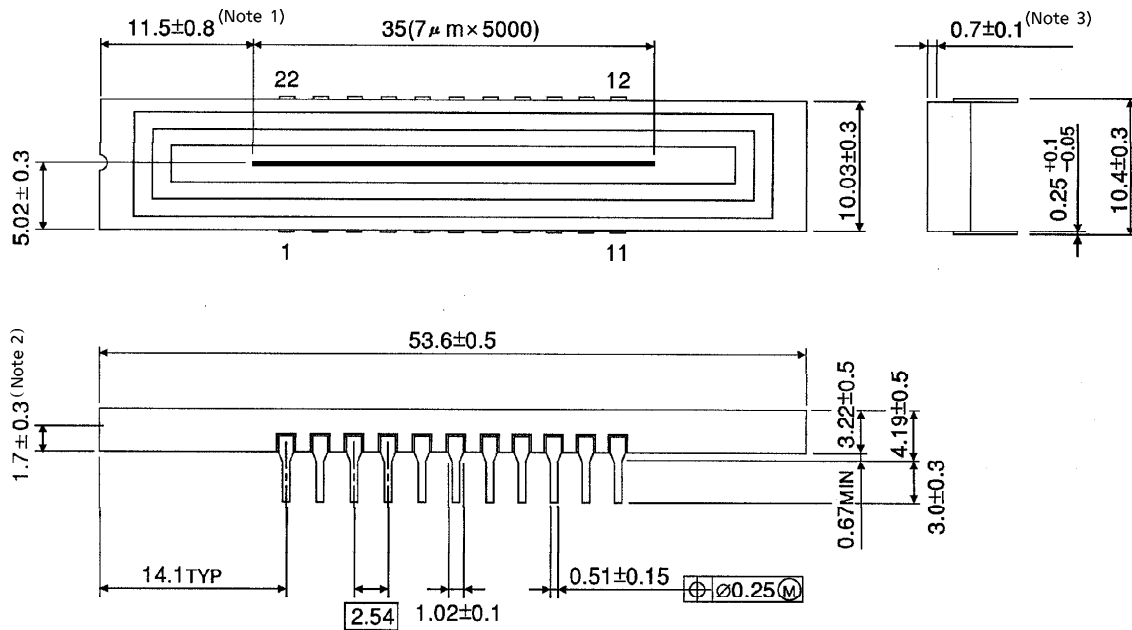
CCD sensor is sensitive to infrared light.

Note that infrared light component degrades resolution and PRNU of CCD sensor.

PACKAGE OUTLINE

WDIP22-C-400-2.54B (A)

Unit in mm



- (Note 1) No. 1 SENSOR ELEMENT (S1) TO EDGE OF PACKAGE.
- (Note 2) TOP OF CHIP TO BOTTOM OF PACKAGE.
- (Note 3) GLASS THICKNES (n = 1.5)

Weight : 5.4g (Typ.)